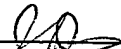
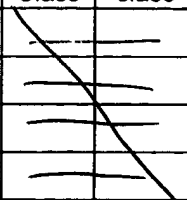
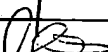


Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)		Applicant <b>Hisashi Ohtani</b>	
		Filing Date September 9, 2003	Group Art Unit <b>2811 2822</b>

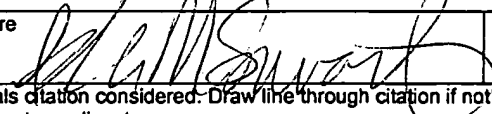
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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
<i>[Signature]</i>	AA	5,485,019	01/16/1996	YAMAZAKI et al.	257	57	02/03/1993
	AB	5,521,107	05/28/1996	YAMAZAKI et al.	438	303	03/29/1994
	AC	5,616,935	04/01/1997	KOYAMA et al.	257	69	02/01/1995
	AD	5,623,157	04/22/1997	MIYAZAKI et al.	257	383	06/07/1995
	AE	5,804,878	09/08/1998	MIYAZAKI et al.	257	764	04/24/1996
	AF	5,849,611	12/15/1998	YAMAZAKI et al.	438	151	05/31/1995
	AG	5,877,513	03/02/1999	KOYAMA et al.	257	66	01/24/1997
	AH	6,013,928	01/11/2000	YAMAZAKI et al.	257	347	06/07/1995
	AI	6,031,290	02/29/2000	MIYAZAKI et al.	257	764	03/13/1998
	AJ	6,124,603	09/26/2000	KOYAMA et al.	257	66	11/23/1998
	AK	6,147,375	11/14/2000	YAMAZAKI et al.	257	296	09/11/1998
	AL	6,166,414	12/26/2000	MIYAZAKI et al.	257	369	08/25/1999
	AM	6,448,612	09/10/2002	MIYAZAKI et al.	257	344	11/02/2000
	AN	6,476,447	11/05/2002	YAMAZAKI et al.	257	350	09/12/2000
	AO	6,492,685	12/10/2002	KOYAMA et al.	257	351	09/20/2000
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Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	AR	JP07-273349	20 OCT 1995	JAPAN			Abstract	
	AS	KR93-0005248	23 MAR 1993	KOREA				No
	AT	KR93-0018736	22 SEP 1993	KOREA				No
	AU	KR94-0016642	23 JUL 1994	KOREA				No
	AV							

Examiner Signature <i>[Signature]</i>	Date Considered <b>3-2-05</b>
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Substitute Form PTO-1449 (Modified)	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. 10/657,137
<b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary) (37 CFR §1.98(b))		Applicant Hisashi Ohtani	
		Filing Date September 9, 2003	Group Art Unit 2811 2822

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
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	AY	
	AZ	

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Substitute Form PTO-1449  
(Modified)U.S. Department of Commerce  
Patent and Trademark OfficeAttorney's Docket No.  
07977-152003Application No.  
10/657,137**Information Disclosure Statement  
by Applicant**

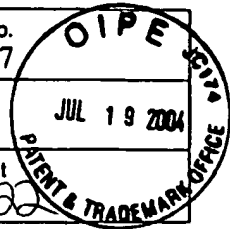
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(37 CFR §1.98(b))

Applicant  
Hisashi OhtaniFiling Date  
September 9, 2003

Group Art Unit

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							Yes	No
<i>[Signature]</i>	AL	06-291314	10/18/1994	JAPAN			Full	
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	AN							
	AO							
	AP							

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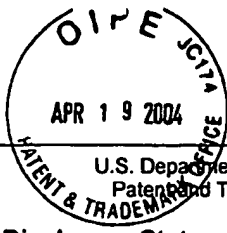
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	Applicant <b>Hisashi Ohtani</b>		
	Filing Date <b>September 9, 2003</b>	Group Art Unit <del>2811</del> <b>2822</b>	

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Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
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	AC	5,889,291	03/30/1999	Koyama et al.	257	59	07/31/1996
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							Yes	No
	AL	05-308128	11/19/1993	JAPAN			ABS	
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	AS	
	AT	

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	Applicant Hisashi Ohtani		
	Filing Date September 9, 2003	Group Art Unit <u>2822</u>	

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	AD	4,808,845	02/1989	Suzuki et al.	326	84	
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	AI	5,343,066	08/1994	Okamoto et al.	257	393	
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Examiner Signature	Date Considered <u>3-2-05</u>
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Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-152003	Application No. New Divisional Application 10/659,137
	Applicant Hisashi Ohtani		
	Filing Date September 9, 2003	Group Art Unit 2822	

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
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<i>[Signature]</i>	ABB	07-135323	05/1995	JAPAN	<del>_____</del>	<del>_____</del>		
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	AEE	07-169975	07/1995	JAPAN	<del>_____</del>	<del>_____</del>		
<i>[Signature]</i>	AFF	07-218932	08/1995	JAPAN	<del>_____</del>	<del>_____</del>		

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Examiner Initial	Desig. ID	Document
<del>_____</del>	AGG	<del>_____</del>
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	AII	<del>_____</del>
	AJJ	<del>_____</del>

Examiner Signature <i>[Signature]</i>	Date Considered 3-2-05
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